

**Search Notes**

Application No.

09/764,243

Examiner

W. David Coleman

Applicant(s)

STEPHENS ET AL.

Art Unit

2823

**SEARCHED**

Class	Subclass	Date	Examiner
438	14	4/16/2004	WDC
716	4	4/16/2004	WDC
430	30	4/16/2004	WDC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	14	4/16/2004	WDC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST 1.4.1 Applicant test a mask reticle option layer by testing transistors on a wafer.	4/16/2004	WDC